## **Electronic Supplementary Information (ESI)**

Reo Amano,<sup>1</sup> Péter Salamon,<sup>2</sup> Shunsuke Yokokawa,<sup>1</sup> Fumiaki Kobayashi,<sup>1</sup> Yuji Sasaki,<sup>1\*</sup> Shuji Fujii,<sup>1</sup> Ágnes Buka,<sup>2</sup> Fumito Araoka,<sup>3</sup> and Hiroshi Orihara<sup>1</sup>

1 Division of Applied Physics, Faculty of Engineering, Hokkaido University North 13 West 8, Kita-ku, Sapporo, Hokkaido 060-8628 (Japan)

2 Institute for Solid State Physics and Optics, Wigner Research Centre for Physics, Hungarian Academy of Sciences, H-1525 Budapest, P.O.B.49 (Hungary.)

3 RIKEN Center for Emergent Matter Science (CEMS), 2-1 Hirosawa, Wako, Saitama 351-0198 (Japan)

\* Corresponding author: yuji.sasaki@eng.hokudai.ac.jp





**Figure S1.** The intensity of diffracted light for each spot as a function of frequency. The sample thickness is 21  $\mu$ m. The intensity is normalized with that of the incident beam. The dashed line is the total power of the light transmitted through the cell. In this case, the power meter is placed right behind the cell.